



Integrated Device Technology, Inc.

HIGH-SPEED CMOS NON-INVERTING BUFFER TRANSCEIVER

IDT54/74AHCT645

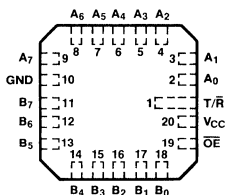
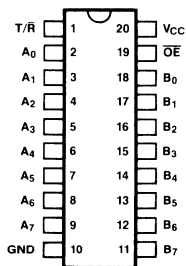
FEATURES:

- Equivalent to ALS speeds and output drive over full temperature and voltage supply extremes
- 8ns typical data to output delay
- $I_{OL} = 14\text{mA}$ over full military temperature range
- CMOS power levels ($5\mu\text{W}$ typ. static)
- Both CMOS and TTL output compatible
- Substantially lower input current levels than ALS ($5\mu\text{A}$ max.)
- Non-inverting buffer transceiver
- 100% product assurance screening to MIL-STD-883, Class B is available
- JEDEC standard pinout for DIP and LCC

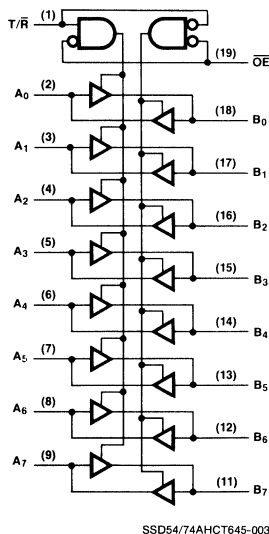
DESCRIPTION:

The IDT54/74AHCT645 are 8-bit non-inverting buffer transceivers built using advanced CEMOS™, a dual metal CMOS technology. These non-inverting buffer transceivers are designed for asynchronous two-way communication between data buses. The devices transmit data from the A bus to the B bus or from the B bus to the A bus, depending upon the level at the direction control (T/R) input. The enable input (\overline{OE}) can be used to disable the device so the buses are effectively isolated.

PIN CONFIGURATIONS



FUNCTIONAL BLOCK DIAGRAM



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MILITARY AND COMMERCIAL TEMPERATURE RANGES

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ABSOLUTE MAXIMUM RATING⁽¹⁾

| SYMBOL | RATING | COMMERCIAL | MILITARY | UNIT |
|-------------------|--------------------------------------|--------------|--------------|------|
| V _{TERM} | Terminal Voltage with Respect to GND | -0.5 to +7.0 | -0.5 to +7.0 | V |
| T _A | Operating Temperature | 0 to +70 | -55 to +125 | °C |
| T _{BIAS} | Temperature Under Bias | -55 to +125 | -65 to +135 | °C |
| T _{STG} | Storage Temperature | -55 to +125 | -65 to +155 | °C |
| I _{OUT} | DC Output Current | 120 | 120 | mA |

NOTE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

T_A = 0°C to +70°C V_{CC} = 5.0V ± 5% Min. = 4.75V Max. = 5.25V (Commercial)

T_A = -55°C to +125°C V_{CC} = 5.0V ± 10% Min. = 4.50V Max. = 5.50V (Military)

V_{LC} = 0.2V

V_{HC} = V_{CC} - 0.2V

| SYMBOL | PARAMETER | TEST CONDITIONS ⁽¹⁾ | MIN. | TYP. ⁽²⁾ | MAX. | UNIT | |
|-----------------|--------------------------------------|--|-----------------------------|---------------------|-----------------|------|-----------------|
| V _{IH} | Input HIGH Level | Guaranteed Logic HIGH Level | 2.0 | — | — | V | |
| V _{IL} | Input LOW Level | Guaranteed Logic LOW Level | — | — | 0.8 | V | |
| I _{IH} | Input HIGH Current (Except I/O Pins) | V _{CC} = Max., V _{IN} = V _{CC} | — | — | 5 | μA | |
| I _{IL} | Input LOW Current (Except I/O Pins) | V _{CC} = Max., V _{IN} = GND | — | — | -5 | μA | |
| I _{SC} | Short Circuit Current | V _{CC} = Max. ⁽³⁾ | -60 | -100 | — | mA | |
| V _{OH} | Output HIGH Voltage | V _{CC} = 3V, V _{IN} = V _{LC} or V _{HC} , I _{OH} = -32μA | V _{HC} | V _{CC} | — | V | |
| | | V _{CC} = Min. V _{IN} = V _{IH} or V _{IL} | I _{OH} = -150μA | V _{HC} | V _{CC} | | — |
| | | | I _{OH} = -12mA MIL | 2.4 | 4.3 | | — |
| V _{OL} | Output LOW Voltage | V _{CC} = 3V, V _{IN} = V _{LC} or V _{HC} , I _{OL} = 300μA | — | GND | V _{LC} | V | |
| | | V _{CC} = Min. V _{IN} = V _{IH} or V _{IL} | I _{OL} = 300μA | — | GND | | V _{LC} |
| | | | I _{OL} = 14mA MIL | — | — | | 0.4 |
| | | I _{OL} = 24mA COM | — | — | 0.5 | | |

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V_{CC} = 5.0V, +25°C ambient and maximum loading.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.

POWER SUPPLY CHARACTERISTICS

$V_{LC} = 0.2V$; $V_{HC} = V_{CC} - 0.2V$

| SYMBOL | PARAMETER | TEST CONDITIONS ⁽¹⁾ | | MIN. | TYP. ⁽²⁾ | MAX. | UNIT |
|-----------|---|--|---|------|---------------------|------|------------|
| I_{CCO} | Quiescent Power Supply Current | $V_{CC} = \text{Max.}$ $V_{IN} \geq V_{HC}$; $V_{IN} \leq V_{LC}$ $f_i = 0$ | | — | 0.001 | 1.5 | mA |
| I_{CCT} | Power Supply Current Per TTL Input HIGH | $V_{CC} = \text{Max.}$ $V_{IN} = 3.4V$ ⁽³⁾ | | — | 0.5 | 1.6 | mA |
| I_{CCD} | Dynamic Power Supply Current | $V_{CC} = \text{Max.}$ Outputs Open OE = GND T/R = GND or V_{CC} One Input Toggling 50% Duty Cycle | $V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ | — | 0.15 | 0.25 | mA/ MHz |
| I_{CC} | Total Power Supply ⁽⁴⁾ Current | $V_{CC} = \text{Max.}$ Outputs Open $f_i = 1.0\text{MHz}$ 50% Duty Cycle OE = GND One Bit Toggling | $V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (AHCT) | — | 0.15 | 1.8 | mA |
| | | | $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$ | — | 0.4 | 2.6 | |
| | | $V_{CC} = \text{Max.}$ Outputs Open $f_i = 250\text{kHz}$ 50% Duty Cycle OE = GND Eight Bits Toggling | $V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (AHCT) | — | 0.3 | 2.0 | |
| | | | $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$ | — | 2.3 | 8.4 | |

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, +25°C ambient and maximum loading.
- Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.

$I_{CC} = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$

$I_{CC} = I_{CCO} + I_{CCT}D_HN_T + I_{CCD}(f_{CP}/2 + f_iN_i)$

I_{CCO} = Quiescent Current

I_{CCT} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current caused by an Input Transition pair (HLH or LHL)

f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)

f_i = Input Frequency

N_i = Number of Inputs at f_i

All currents are in milliamps and all frequencies are in megahertz.

DEFINITION OF FUNCTIONAL TERMS

| PIN NAMES | DESCRIPTION |
|------------------------|--|
| \overline{OE} T/R | Output Enable Input (Active LOW) Transmit/Receive Input |
| A_0 - A_7 | Side A Inputs or 3-State Outputs |
| B_0 - B_7 | Side B Inputs or 3-State Outputs |

FUNCTION TABLE

| INPUTS | | OPERATION |
|-----------------|-----|---------------------|
| \overline{OE} | T/R | |
| L | L | Bus B Data to Bus A |
| L | H | Bus A Data to Bus B |
| H | X | Isolation |

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

| SYMBOL | PARAMETER | CONDITION | TYPICAL | COMMERCIAL | | MILITARY | | UNITS |
|------------------------|---------------------------------------|---|---------|------------|------|----------|------|-------|
| | | | | MIN. | MAX. | MIN. | MAX. | |
| t_{PLH} t_{PHL} | Propagation Delay A to B B to A | $C_L = 50\text{ pf}$ $R_L = 500\Omega$ | 8.0 | 3.0 | 10.0 | 3.0 | 15.0 | ns |
| t_{ZH} t_{ZL} | Output Enable Time | | 15.0 | 5.0 | 20.0 | 5.0 | 25.0 | ns |
| t_{HZ} t_{LZ} | Output Disable Time | | 11.0 | 2.0 | 15.0 | 2.0 | 18.0 | ns |
| t_{DLH} t_{DHL} | Propagation Delay T/R to A or B* | | 15.0 | — | — | — | — | ns |

*Guaranteed by Design

